

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/776,431	ABBAR ET AL.
	Examiner	Art Unit
	Cong-Lac Huynh	2178

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (US PAT, USPGPUB, JPO, EPO, Derwent)	10/11/2006	CLH
ACM	10/17/2006	CLH
IEEE	10/25/2006	CLH
ProQuest	10/25/2006	CLH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
715	500	10/11/2006	CLH
Interference Search History Printout		10/11/2006	CLH